

Notice of References Cited	Application/Control No. 10/588,833		Applicant(s)/Patent Under Reexamination LIEBER ET AL.	
	Examiner DAREN WOLVERTON		Art Unit 2813	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,897,098	05-2005	Hareland et al.	438/128
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Deng, F. et al. "Salicidation process using NiSi and its device application", 15 June 1997, Journal of Applied Physics 81 (12), 8047-8051.
	V	Zhang, Z. et al. "Electrically robust ultralong nanowires of NiSi, Ni ₂ Si, and Ni ₃₁ Si ₁₂ ", 24 January 2006, Applied Physics Letters 88, 043104 (2006)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.